Notice of References Cited Application/Control No. Applicant(s)/Patent Under Reexamination HIGASHIKAWA, IWAO Examiner Art Unit Page 1 of 1 U.S. PATENT DOCUMENTS Applicant(s)/Patent Under Reexamination HIGASHIKAWA, IWAO Page 1 of 1

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,015,866	05-1991	Hayashi, Yutaka	250/548
	В	US-			
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	_	US-			
	٦	US-			
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

HON-FAILINI DOCOMENTO						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	×					

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.